

Test Report

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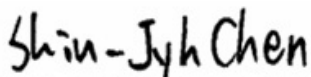
SFI ELECTRONICS TECHNOLOGY INC.



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : TRANSIENT VOLTAGE SUPPRESSORS (T. V. S) SMD
MULTILAYE
Style/Item No. : FULL SIZE (A SERIES, C SERIES, ESD SERIES, CH SERIES)
V150
Sample Receiving Date : 2008/03/18
Testing Period : 2008/03/18 TO 2008/03/27

=====
Test Result(s) : Please refer to next page(s).



Shin-jyh Chen / Asst. Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei

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Test Result(s)

PART NAME NO.1 : TRANSIENT VOLTAGE SUPPRESSORS (T. V. S) SMD
MULTILAYE

Test Item (s):	Unit	Method	MDL	Result
				No.1
PFOS	mg/kg	With reference to US EPA 3540C : 1996 method for PFOS Content. Analysis was performed by LC/MS.	1	n.d.

- Note :
1. mg/kg = ppm
 2. n.d. = Not Detected
 3. MDL = Method Detection Limit

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** End of Report **